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		APPLICANT: Hilal EZZEDDINE et al.			
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Sheet	1	of	1		

U.S. PATENT DOCUMENTS

Examiner's Initials	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication or of issue of Cited Document MM-DD-YYYY
		Number	Kind Code		
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Examiner's Initials	Cite No.	Foreign Patent Document			Name of Patentee or Applicant of Cited Document (not necessary)	Date of Publication of Cited Document MM-DD-YYYY	Translation (Y/N)
		Office/Country	Number	Kind Code			

OTHER ART — NON PATENT LITERATURE DOCUMENTS

Examiner's Initials	Cite No	Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s), publisher, city and/or country where published.	Translation (Y/N)
DT		French Search Report from French Patent Application 02/15477, filed December 6, 2002	
DT		Ojha S. et al. "Reduced Size RF Coupler Design For Specialized Load Requirements" Circuits and Systems, 1997. Proceedings Of The 40 th Midwest Symposium on Sacramento, CA, USA 3-6 Aug. 1997, New York, NY USA, IEEE, US, August 3, 1997, pages 595-598	
DT		Patent Abstracts of Japan, vol. 005, no. 125 (E-069), August 12, 1981 & JP 56 062402 A (Fujitsu Ltd.) May 28, 1981	
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EXAMINER <i>Dean Tokuda</i>	DATE CONSIDERED <i>2/23/05</i>
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